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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	125
Number of Gates	36000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	160-BQFP
Supplier Device Package	160-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx24-pq160

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3 40MX and 42MX FPGAs

3.1 General Description

Microsemi's 40MX and 42MX families offer a cost-effective design solution at 5V. The MX devices are single-chip solutions and provide high performance while shortening the system design and development cycle. MX devices can integrate and consolidate logic implemented in multiple PALs, CPLDs, and FPGAs. Example applications include high-speed controllers and address decoding, peripheral bus interfaces, DSP, and co-processor functions.

The MX device architecture is based on Microsemi's patented antifuse technology implemented in a 0.45µm triple-metal CMOS process. With capacities ranging from 3,000 to 54,000 system gates, the MX devices provide performance up to 250 MHz, are live on power-up and have one-fifth the standby power consumption of comparable FPGAs. MX FPGAs provide up to 202 user I/Os and are available in a wide variety of packages and speed grades.

A42MX24 and A42MX36 devices also feature multiPlex I/Os, which support mixed-voltage systems, enable programmable PCI, deliver high-performance operation at both 5.0V and 3.3V, and provide a low-power mode. The devices are fully compliant with the PCI local bus specification (version 2.1). They deliver 200 MHz on-chip operation and 6.1 ns clock-to-output performance.

The 42MX24 and 42MX36 devices include system-level features such as IEEE Standard 1149.1 (JTAG) Boundary Scan Testing and fast wide-decode modules. In addition, the A42MX36 device offers dual-port SRAM for implementing fast FIFOs, LIFOs, and temporary data storage. The storage elements can efficiently address applications requiring wide data path manipulation and can perform transformation functions such as those required for telecommunications, networking, and DSP.

All MX devices are fully tested over automotive and military temperature ranges. In addition, the largest member of the family, the A42MX36, is available in both CQ208 and CQ256 ceramic packages screened to MIL-STD-883 levels. For easy prototyping and conversion from plastic to ceramic, the CQ208 and PQ208 devices are pin-compatible.

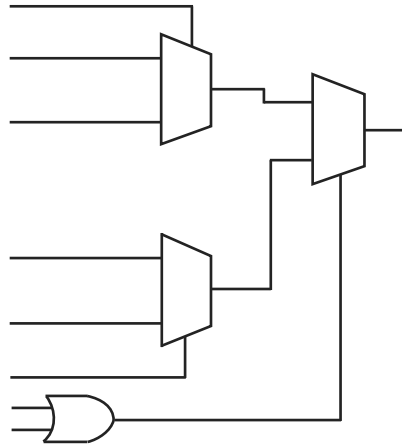
3.2 MX Architectural Overview

The MX devices are composed of fine-grained building blocks that enable fast, efficient logic designs. All devices within these families are composed of logic modules, I/O modules, routing resources and clock networks, which are the building blocks for fast logic designs. In addition, the A42MX36 device contains embedded dual-port SRAM modules, which are optimized for high-speed data path functions such as FIFOs, LIFOs and scratch pad memory. A42MX24 and A42MX36 also contain wide-decode modules.

3.2.1 Logic Modules

The 40MX logic module is an eight-input, one-output logic circuit designed to implement a wide range of logic functions with efficient use of interconnect routing resources.(see the following figure).

The logic module can implement the four basic logic functions (NAND, AND, OR and NOR) in gates of two, three, or four inputs. The logic module can also implement a variety of D-latches, exclusivity functions, AND-ORs and OR-ANDs. No dedicated hard-wired latches or flip-flops are required in the array; latches and flip-flops can be constructed from logic modules whenever required in the application.

Figure 2 • 42MX C-Module Implementation

The 42MX devices contain three types of logic modules: combinatorial (C-modules), sequential (S-modules) and decode (D-modules). The following figure illustrates the combinatorial logic module. The S-module, shown in Figure 4, page 8, implements the same combinatorial logic function as the C-module while adding a sequential element. The sequential element can be configured as either a D-flip-flop or a transparent latch. The S-module register can be bypassed so that it implements purely combinatorial logic.

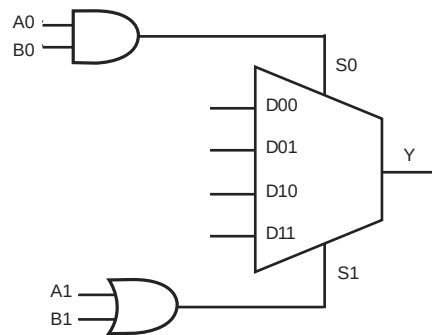
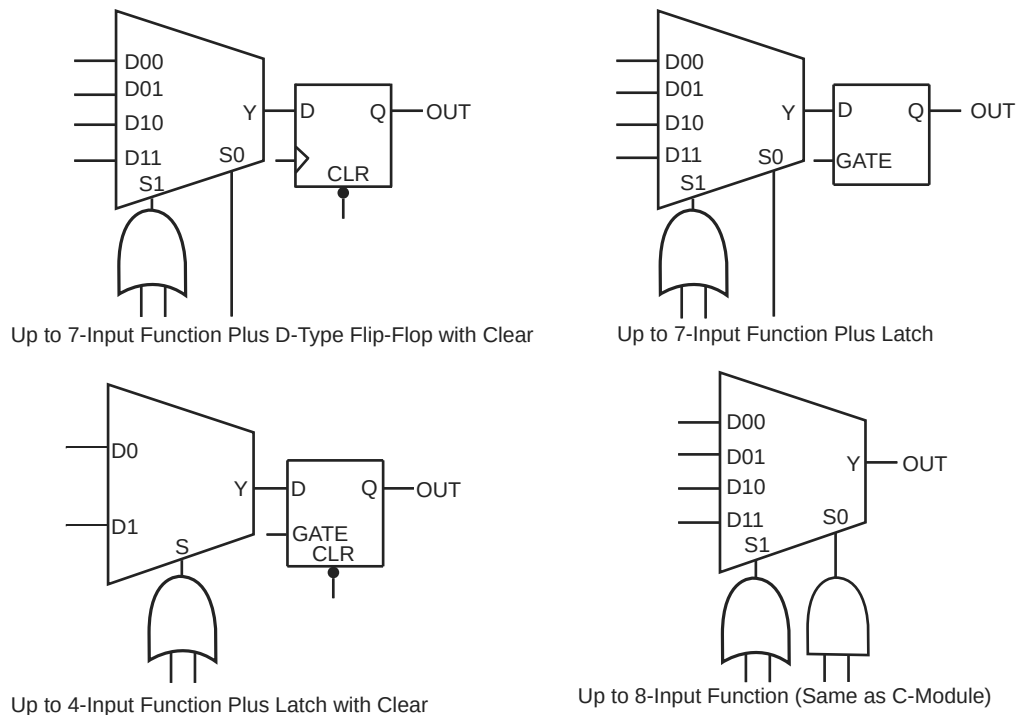
Figure 3 • 42MX C-Module Implementation

Figure 4 • 42MX S-Module Implementation

A42MX24 and A42MX36 devices contain D-modules, which are arranged around the periphery of the device. D-modules contain wide-decode circuitry, providing a fast, wide-input AND function similar to that found in CPLD architectures (Figure 5, page 9). The D-module allows A42MX24 and A42MX36 devices to perform wide-decode functions at speeds comparable to CPLDs and PALs. The output of the D-module has a programmable inverter for active HIGH or LOW assertion. The D-module output is hardwired to an output pin, and can also be fed back into the array to be incorporated into other logic.

3.2.2 Dual-Port SRAM Modules

The A42MX36 device contains dual-port SRAM modules that have been optimized for synchronous or asynchronous applications. The SRAM modules are arranged in 256-bit blocks that can be configured as 32x8 or 64x4. SRAM modules can be cascaded together to form memory spaces of user-definable width and depth. A block diagram of the A42MX36 dual-port SRAM block is shown in Figure 6, page 9.

The A42MX36 SRAM modules are true dual-port structures containing independent read and write ports. Each SRAM module contains six bits of read and write addressing (RDAD[5:0] and WRAD[5:0], respectively) for 64x4-bit blocks. When configured in byte mode, the highest order address bits (RDAD5 and WRAD5) are not used. The read and write ports of the SRAM block contain independent clocks (RCLK and WCLK) with programmable polarities offering active HIGH or LOW implementation. The SRAM block contains eight data inputs (WD[7:0]), and eight outputs (RD[7:0]), which are connected to segmented vertical routing tracks.

The A42MX36 dual-port SRAM blocks provide an optimal solution for high-speed buffered applications requiring FIFO and LIFO queues. The ACTgen Macro Builder within Microsemi's designer software provides capability to quickly design memory functions with the SRAM blocks. Unused SRAM blocks can be used to implement registers for other user logic within the design.

- VCCA = Power supply in volts (V)
- F = Switching frequency in megahertz (MHz)

3.4.4 Equivalent Capacitance

Equivalent capacitance is calculated by measuring ICC_{active} at a specified frequency and voltage for each circuit component of interest. Measurements have been made over a range of frequencies at a fixed value of VCC. Equivalent capacitance is frequency-independent, so the results can be used over a wide range of operating conditions. Equivalent capacitance values are shown below.

3.4.5 C_{EQ} Values for Microsemi MX FPGAs

Modules (C_{EQM}) 3.5

Input Buffers (C_{EQI}) 6.9

Output Buffers (C_{EQO}) 18.2

Routed Array Clock Buffer Loads (C_{EQCR}) 1.4

To calculate the active power dissipated from the complete design, the switching frequency of each part of the logic must be known. The equation below shows a piece-wise linear summation over all components.

$$\begin{aligned} \text{Power} = & VCCA^2 * [(m \times C_{EQM} * f_m)_{\text{modules}} + (n * C_{EQI} * f_n)_{\text{inputs}} + (p * (C_{EQO} + C_L) * f_p)_{\text{outputs}} + \\ & 0.5 * (q_1 * C_{EQCR} * f_{q1})_{\text{routed_Clk1}} + (r_1 * f_{q1})_{\text{routed_Clk1}} + \\ & 0.5 * (q_2 * C_{EQCR} * f_{q2})_{\text{routed_Clk2}} + (r_2 * f_{q2})_{\text{routed_Clk2}}] \end{aligned} \quad (2)$$

EQ 3

where:

m = Number of logic modules switching at frequency f_m

n = Number of input buffers switching at frequency f_n

p = Number of output buffers switching at frequency f_p

q₁ = Number of clock loads on the first routed array clock

q₂ = Number of clock loads on the second routed array clock

r₁ = Fixed capacitance due to first routed array clock

r₂ = Fixed capacitance due to second routed array clock

C_{EQM} = Equivalent capacitance of logic modules in pF

C_{EQI} = Equivalent capacitance of input buffers in pF

C_{EQO} = Equivalent capacitance of output buffers in pF

C_{EQCR} = Equivalent capacitance of routed array clock in pF

C_L = Output load capacitance in pF

f_m = Average logic module switching rate in MHz

f_n = Average input buffer switching rate in MHz

f_p = Average output buffer switching rate in MHz

f_{q1} = Average first routed array clock rate in MHz

Table 34 • A40MX02 Timing Characteristics (Nominal 5.0 V Operation) (continued)
(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad HIGH		3.3		3.8		4.3		5.1		7.2	ns
t _{DHL}	Data-to-Pad LOW		4.0		4.6		5.2		6.1		8.6	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.3		4.9		5.8		8.0	ns
t _{ENZL}	Enable Pad Z to LOW		4.7		5.4		6.1		7.2		10.1	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.9		9.1		10.4		12.2		17.1	ns
t _{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d _{TLH}	Delta LOW to HIGH		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{THL}	Delta HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF
CMOS Output Module Timing ⁴												
t _{DLH}	Data-to-Pad HIGH		3.9		4.5		5.1		6.05		8.5	ns
t _{DHL}	Data-to-Pad LOW		3.4		3.9		4.4		5.2		7.3	ns
t _{ENZH}	Enable Pad Z to HIGH		3.4		3.9		4.4		5.2		7.3	ns
t _{ENZL}	Enable Pad Z to LOW		4.9		5.6		6.4		7.5		10.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		7.9		9.1		10.4		12.2		17.0	ns
t _{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d _{TLH}	Delta LOW to HIGH		0.03		0.04		0.04		0.05		0.07	ns/pF
d _{THL}	Delta HIGH to LOW		0.02		0.02		0.03		0.03		0.04	ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.
4. Delays based on 35pF loading

Table 35 • A40MX02 Timing Characteristics (Nominal 3.3 V Operation)
(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays												
t _{PD1}	Single Module		1.7		2.0		2.3		2.7		3.7	ns
t _{PD2}	Dual-Module Macros		3.7		4.3		4.9		5.7		8.0	ns
t _{CO}	Sequential Clock-to-Q		1.7		2.0		2.3		2.7		3.7	ns
t _{GO}	Latch G-to-Q		1.7		2.0		2.3		2.7		3.7	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.7		2.0		2.3		2.7		3.7	ns
Logic Module Predicted Routing Delays ¹												

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH		1.5		1.6		1.8		2.17		3.0		ns
t _{INYL}	Pad-to-Y LOW		1.2		1.3		1.4		1.7		2.4		ns
t _{INGH}	G to Y HIGH		1.8		2.0		2.3		2.7		3.7		ns
t _{INGL}	G to Y LOW		1.8		2.0		2.3		2.7		3.7		ns
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay		2.8		3.2		3.6		4.2		5.9		ns
t _{IRD2}	FO = 2 Routing Delay		3.2		3.5		4.0		4.7		6.6		ns
t _{IRD3}	FO = 3 Routing Delay		3.5		3.9		4.4		5.2		7.3		ns
t _{IRD4}	FO = 4 Routing Delay		3.9		4.3		4.9		5.7		8.0		ns
t _{IRD8}	FO = 8 Routing Delay		5.2		5.8		6.6		7.7		10.8		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	4.1		4.5		5.1		6.0		8.4		ns
		FO = 256	4.5		5.0		5.6		6.7		9.3		ns
t _{CKL}	Input HIGH to LOW	FO = 32	5.0		5.5		6.2		7.3		10.2		ns
		FO = 256	5.4		6.0		6.8		8.0		11.2		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	1.7		1.9		2.1		2.5		3.5		ns
		FO = 256	1.9		2.1		2.3		2.7		3.8		ns
t _{PWL}	Minimum Pulse Width LOW	FO = 32	1.7		1.9		2.1		2.5		3.5		ns
		FO = 256	1.9		2.1		2.3		2.7		3.8		ns
t _{CKSW}	Maximum Skew	FO = 32	0.4		0.5		0.5		0.6		0.9		ns
		FO = 256	0.4		0.5		0.5		0.6		0.9		ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 256	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	3.3		3.7		4.2		4.9		6.9		ns
		FO = 256	3.7		4.1		4.6		5.5		7.6		ns
t _P	Minimum Period	FO = 32	5.6		6.2		6.7		7.8		12.9		ns
		FO = 256	6.1		6.8		7.4		8.5		14.2		ns
f _{MAX}	Maximum Frequency	FO = 32	177		161		148		129		77		MHz
		FO = 256	161		146		135		117		70		MHz

Table 39 • A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		3.4		3.8		4.3		5.1		7.1	ns
t _{DHL}	Data-to-Pad LOW		4.0		4.5		5.1		6.1		8.3	ns
t _{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t _{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t _{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t _{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t _{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t _{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t _{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t _{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad),64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d _{TLH}	Capacity Loading, LOW to HIGH		0.00		0.00		0.00		0.10		0.01	ns/pF
d _{THL}	Capacity Loading, HIGH to LOW		0.09		0.10		0.10		0.10		0.10	ns/pF

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{PWL}	Minimum Pulse Width LOW	FO = 32	5.3		5.9		6.7		7.8		11.0		ns
		FO = 384	6.2		6.9		7.9		9.2		12.9		ns
t _{CKSW}	Maximum Skew	FO = 32		0.5		0.5		0.6		0.7		1.0	ns
		FO = 384		2.2		2.4		2.7		3.2		4.5	ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 384	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	3.9		4.3		4.9		5.7		8.0		ns
		FO = 384	4.5		4.9		5.6		6.6		9.2		ns
t _p	Minimum Period	FO = 32	7.0		7.8		8.4		9.7		16.2		ns
		FO = 384	7.7		8.6		9.3		10.7		17.8		ns
f _{MAX}	Maximum Frequency	FO = 32		142		129		119		103		62	MHz
		FO = 384		129		117		108		94		56	MHz
TTL Output Module Timing ⁵													
t _{DLH}	Data-to-Pad HIGH			3.5		3.9		4.4		5.2		7.3	ns
t _{DHL}	Data-to-Pad LOW			4.1		4.6		5.2		6.1		8.6	ns
t _{ENZH}	Enable Pad Z to HIGH			3.8		4.2		4.8		5.6		7.8	ns
t _{ENZL}	Enable Pad Z to LOW			4.2		4.6		5.3		6.2		8.7	ns
t _{ENHZ}	Enable Pad HIGH to Z			7.6		8.4		9.5		11.2		15.7	ns
t _{ENLZ}	Enable Pad LOW to Z			7.0		7.8		8.8		10.4		14.5	ns
t _{GLH}	G-to-Pad HIGH			4.8		5.3		6.0		7.2		10.0	ns
t _{GHL}	G-to-Pad LOW			4.8		5.3		6.0		7.2		10.0	ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading			8.0		8.9		10.1		11.9		16.7	ns
t _{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading			11.3		12.5		14.2		16.7		23.3	ns
d _{TLH}	Capacitive Loading, LOW to HIGH			0.04		0.04		0.05		0.06		0.08	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW			0.05		0.05		0.06		0.07		0.10	ns/pF
CMOS Output Module Timing ⁵													
t _{DLH}	Data-to-Pad HIGH			4.5		5.0		5.6		6.6		9.3	ns
t _{DHL}	Data-to-Pad LOW			3.4		3.8		4.3		5.1		7.1	ns
t _{ENZH}	Enable Pad Z to HIGH			3.8		4.2		4.8		5.6		7.8	ns
t _{ENZL}	Enable Pad Z to LOW			4.2		4.6		5.3		6.2		8.7	ns
t _{ENHZ}	Enable Pad HIGH to Z			7.6		8.4		9.5		11.2		15.7	ns
t _{ENLZ}	Enable Pad LOW to Z			7.0		7.8		8.8		10.4		14.5	ns
t _{GLH}	G-to-Pad HIGH			7.1		7.9		8.9		10.5		14.7	ns
t _{GHL}	G-to-Pad LOW			7.1		7.9		8.9		10.5		14.7	ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading			8.0		8.9		10.1		11.9		16.7	ns

Table 42 • A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵												
t _{DLH}	Data-to-Pad HIGH		2.4		2.7		3.1		3.6		5.1	ns
t _{DHL}	Data-to-Pad LOW		2.8		3.2		3.6		4.2		5.9	ns
t _{ENZH}	Enable Pad Z to HIGH		2.5		2.8		3.2		3.8		5.3	ns
t _{ENZL}	Enable Pad Z to LOW		2.8		3.1		3.5		4.2		5.9	ns
t _{ENHZ}	Enable Pad HIGH to Z		5.2		5.7		6.5		7.6		10.7	ns
t _{ENLZ}	Enable Pad LOW to Z		4.8		5.3		6.0		7.1		9.9	ns
t _{GLH}	G-to-Pad HIGH		2.9		3.2		3.6		4.3		6.0	ns
t _{GHL}	G-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t _{LSU}	I/O Latch Output Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t _{LH}	I/O Latch Output Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		5.6		6.1		6.9		8.1		11.4	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.6		11.8		13.4		15.7		22.0	ns
d _{TLH}	Capacitive Loading, LOW to HIGH		0.04		0.04		0.04		0.05		0.07	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

Table 43 • A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL Output Module Timing ⁵ (continued)													
t _{LH}	I/O Latch Output Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O			7.7		8.5		9.6		11.3		15.9	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O			14.8		16.5		18.7		22.0		30.8	ns
d _{TLH}	Capacitive Loading, LOW to HIGH			0.05		0.05		0.06		0.07		0.10	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW			0.04		0.04		0.05		0.06		0.08	ns/pF
CMOS Output Module Timing ⁵													
t _{DLH}	Data-to-Pad HIGH			4.8		5.3		5.5		6.4		9.0	ns
t _{DHL}	Data-to-Pad LOW			3.5		3.9		4.1		4.9		6.8	ns
t _{ENZH}	Enable Pad Z to HIGH			3.6		4.0		4.5		5.3		7.4	ns
t _{ENZL}	Enable Pad Z to LOW			3.4		4.0		5.0		5.8		8.2	ns
t _{ENHZ}	Enable Pad HIGH to Z			7.2		8.0		9.0		10.7		14.9	ns
t _{ENLZ}	Enable Pad LOW to Z			6.7		7.5		8.5		9.9		13.9	ns
t _{GLH}	G-to-Pad HIGH			6.8		7.6		8.6		10.1		14.2	ns
t _{GHL}	G-to-Pad LOW			6.8		7.6		8.6		10.1		14.2	ns
t _{LSU}	I/O Latch Set-Up		0.7		0.7		0.8		1.0		1.4		ns
t _{LH}	I/O Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O			7.7		8.5		9.6		11.3		15.9	ns
t _{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O			14.8		16.5		18.7		22.0		30.8	ns
d _{TLH}	Capacitive Loading, LOW to HIGH			0.05		0.05		0.06		0.07		0.10	ns/pF
d _{THL}	Capacitive Loading, HIGH to LOW			0.04		0.04		0.05		0.06		0.08	ns/pF
t _{HEXT}	Input Latch External Hold	FO = 32	3.9		4.3		4.9		5.7		8.1		ns
		FO = 486	4.6		5.2		5.8		6.9		9.6		ns
t _P	Minimum Period (1/f _{MAX})	FO = 32	7.8		8.7		9.5		10.8		18.2		ns
		FO = 486	8.6		9.5		10.4		11.9		19.9		ns

1. For dual-module macros, use t_{PD1} + t_{RD1} + t_{PDn}, t_{CO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDI, I/O Test Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDO, I/O Test Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TMS, I/O Test Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a 10k Ω pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

VCC, Supply Voltage

Input supply voltage for 40MX devices

VCCA, Supply Voltage

Supply voltage for array in 42MX devices

VCCI, Supply Voltage

Supply voltage for I/Os in 42MX devices

WD, I/O Wide Decode Output

When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.

Table 47 • PL44

PL44		
Pin Number	A40MX02 Function	A40MX04 Function
21	GND	GND
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	VCC	VCC
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	GND	GND
33	CLK, I/O	CLK, I/O
34	MODE	MODE
35	VCC	VCC
36	SDI, I/O	SDI, I/O
37	DCLK, I/O	DCLK, I/O
38	PRA, I/O	PRA, I/O
39	PRB, I/O	PRB, I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	GND	GND
44	I/O	I/O

Table 52 • PQ160

PQ160			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
58	VCCI	VCCI	VCCI
59	GND	GND	GND
60	VCCA	VCCA	VCCA
61	LP	LP	LP
62	I/O	I/O	TCK, I/O
63	I/O	I/O	I/O
64	GND	GND	GND
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	I/O	I/O	I/O
69	GND	GND	GND
70	NC	I/O	I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	NC	I/O	I/O
76	I/O	I/O	I/O
77	NC	I/O	I/O
78	I/O	I/O	I/O
79	NC	I/O	I/O
80	GND	GND	GND
81	I/O	I/O	I/O
82	SDO, I/O	SDO, I/O	SDO, TDO, I/O
83	I/O	I/O	WD, I/O
84	I/O	I/O	WD, I/O
85	I/O	I/O	I/O
86	NC	VCCI	VCCI
87	I/O	I/O	I/O
88	I/O	I/O	WD, I/O
89	GND	GND	GND
90	NC	I/O	I/O
91	I/O	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O

Figure 44 • PQ208

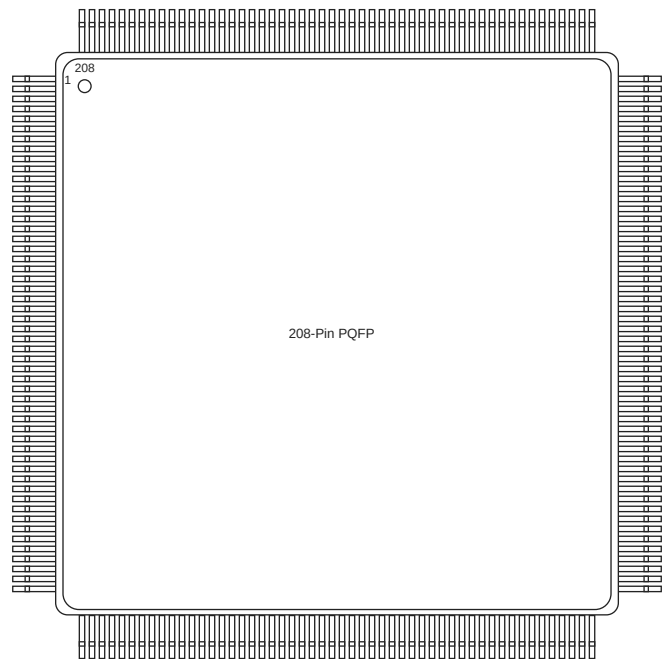


Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
1	GND	GND	GND
2	NC	VCCA	VCCA
3	MODE	MODE	MODE
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	NC	I/O	I/O
10	NC	I/O	I/O
11	NC	I/O	I/O
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	NC	I/O	I/O
17	VCCA	VCCA	VCCA
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	I/O	I/O	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
200	I/O
201	I/O
202	I/O
203	I/O
204	I/O
205	I/O
206	VCCA
207	I/O
208	I/O
209	VCCA
210	VCCI
211	I/O
212	I/O
213	I/O
214	I/O
215	I/O
216	I/O
217	I/O
218	I/O
219	VCCA
220	I/O
221	I/O
222	I/O
223	I/O
224	I/O
225	I/O
226	I/O
227	VCCI
228	I/O
229	I/O
230	I/O
231	I/O
232	I/O
233	I/O
234	I/O
235	I/O
236	I/O

Table 56 • VQ100

VQ100		
Pin Number	A42MX09 Function	A42MX16 Function
57	I/O	I/O
58	I/O	I/O
59	I/O	I/O
60	I/O	I/O
61	I/O	I/O
62	LP	LP
63	VCCA	VCCA
64	VCCI	VCCI
65	VCCA	VCCA
66	I/O	I/O
67	I/O	I/O
68	I/O	I/O
69	I/O	I/O
70	GND	GND
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	I/O	I/O
75	I/O	I/O
76	I/O	I/O
77	SDI, I/O	SDI, I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O
81	I/O	I/O
82	GND	GND
83	I/O	I/O
84	I/O	I/O
85	PRA, I/O	PRA, I/O
86	I/O	I/O
87	CLKA, I/O	CLKA, I/O
88	VCCA	VCCA
89	I/O	I/O
90	CLKB, I/O	CLKB, I/O
91	I/O	I/O
92	PRB, I/O	PRB, I/O

Table 58 • CQ208

CQ208	
Pin Number	A42MX36 Function
37	I/O
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	I/O
46	I/O
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	GND
53	GND
54	TMS, I/O
55	TDI, I/O
56	I/O
57	WD, I/O
58	WD, I/O
59	I/O
60	VCCI
61	I/O
62	I/O
63	I/O
64	I/O
65	QCLKA, I/O
66	WD, I/O
67	WD, I/O
68	I/O
69	I/O
70	WD, I/O
71	WD, I/O
72	I/O
73	I/O

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
244	WD, I/O
245	I/O
246	I/O
247	I/O
248	VCCI
249	I/O
250	WD, I/O
251	WD, I/O
252	I/O
253	SDI, I/O
254	I/O
255	GND
256	NC

Figure 51 • BG272

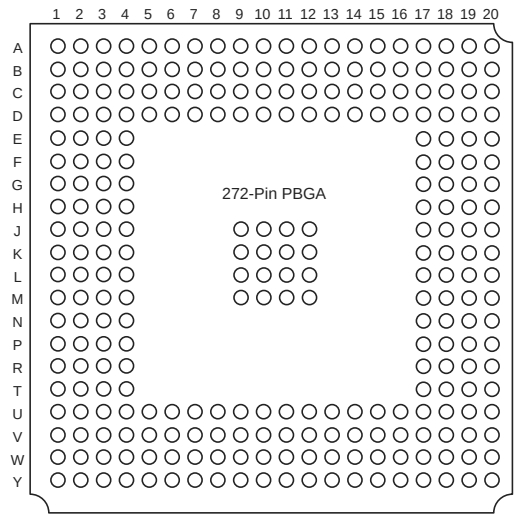


Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
A1	GND
A2	GND
A3	I/O
A4	WD, I/O
A5	I/O

Table 62 • CQ172

21	I/O
22	GND
23	VCCI
24	VSV
25	I/O
26	I/O
27	VCC
28	I/O
29	I/O
30	I/O
31	I/O
32	GND
33	I/O
34	I/O
35	I/O
36	I/O
37	GND
38	I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	BININ
45	BINOUT
46	I/O
47	I/O
48	I/O
49	I/O
50	VCCI
51	I/O
52	I/O
53	I/O
54	I/O
55	GND
56	I/O
57	I/O
58	I/O
59	I/O